



Atty. Dkt. No. 039153-0405 (F0945)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Uzodinma Okoroanyanwu et al.

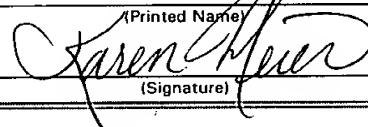
Title: IMPROVING SEM INSPECTION
AND ANALYSIS OF
PATTERNEDE PHOTORESIST
FEATURES

Appl. No.: 09/820,143

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Examiner: Mary A. El Shammaa

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AMENDMENT AND REPLY UNDER 37 CFR 1.111

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Commissioner for Patents
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This communication is responsive to the Non-Final Office Action dated August 6, 2003, concerning the above-referenced patent application.

Amendments to the Specification begin on page 2 of this document.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this document.

Amendments to the Drawings begin on page 6 of this document, and include a copy of the Formal Drawings filed June 11, 2001.

Remarks/Arguments begin on page 7 of this document.

Please amend the application as follows: